

# 電子部品検査用メッシュプローブ

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## Mesh-Probe for Electronic Device

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### Abstract

A membrane-type material used in electronic circuit inspections was developed. This material can be used to produce narrow pitches at a low cost. It has a durability under repeated tests, up to 1 million runs using a QFN (Quad Flat Non-leaded package). When examined, the characteristics of electricity, conductor resistance, insulation resistance, withstand voltage and current-carrying capacity were tested. It was confirmed that the acceptable level was achieved without any problems as a contact probe.

**Key Words:** *Mesh-Probe, Durability, Conductor Resistance, Insulation Resistance, Withstand Voltage, Current-Carrying Capacity, Flexibility*